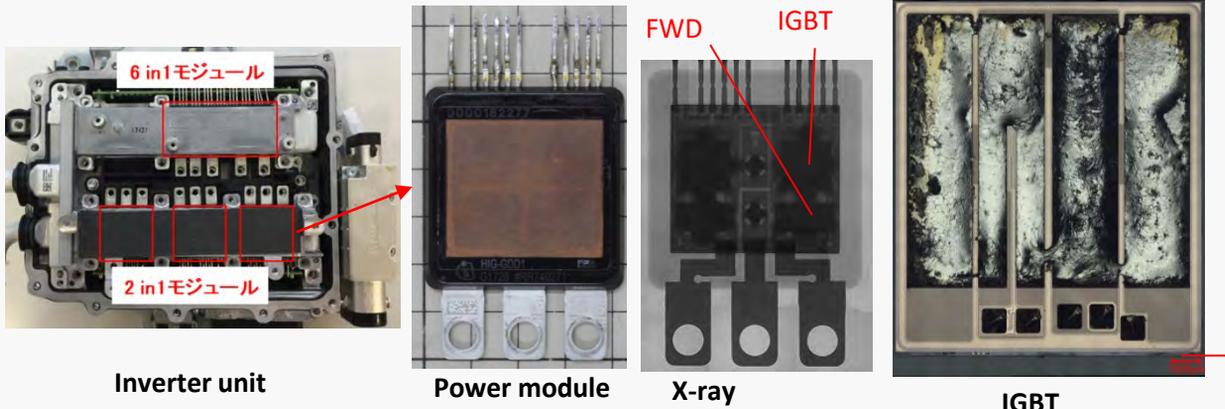


INFINEON 2 in 1* POWER MODULE STRUCTURE ANALYSIS REPORT – Product used in the Hyundai IONIQ PHEV



* One IGBT and one free-wheeling diode form one pair. There are two pairs in one package. This is referred to as 2 in 1. There are two types of power modules in this inverter unit: one is 2 in 1, the other is 6 in 1. We analyzed the 2 in 1 inverter.

Product outline

The Electric Power Control Unit (EPCU) found within the 2018 Hyundai IONIQ PHEV uses Infineon's third generation half-bridge IGBT power module. This product is estimated to be equivalent to Infineon's "FF400R07A01E3_S6" 700V/400A component, a part of the HybridPACK™ family.

Basic features

- Double-sided cooling structure with DBC boards are attached to both sides of the package.
- A spacer is used to connect the IGBT die to the DBC board within the package.
- There are current sense, emitter sense, and temperature sense pads on the IGBT chip.
- The IGBT process is estimated to be equivalent to TRENCHSTOP™ IGBT3.

Report contents

- Estimation of the internal layout from the results of module plane analysis.
- Cross section and material analysis with focus on components of the double-sided cooling structure.
- IGBT die analysis: plane and cross-section analysis of the cell area and the die edge.
- The area and area ratio of the current sensing emitter are calculated from plane observations.
- Structure analysis of the temperature sense diode.
- Thermal resistance estimation based on structural analysis results.

Report price: \$6,500

Note: The report price may change over time. For current price contact info@ltecusa.com.

19G-0040-1

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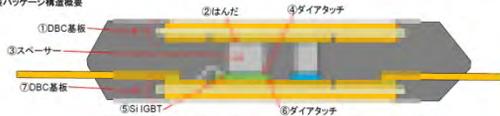
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Excerpts from the analysis report

表 4: 実装パッケージ構造概要



番号	測定箇所	測長	材料
1	基板 (DBC)		
1-1	上銅箔層		
1-2	絶縁層		
1-3	添加物		
1-4	下銅箔層		
2	はんだ		
3	スペース		
4	ダイアタッチ		
5	IGBT		
5-1	表面保護膜		
5-2	パッシベーション		
5-3	基板		
5-4	集電電極-1		
5-5	集電電極-2		
5-6	表面電極-3		
5-7	表面電極-4		
6	ダイアタッチ		
7	基板 (DBC)		
7-1	上銅箔層		
7-2	絶縁層		
7-3	添加物		
7-4	下銅箔層		

2-2. パッケージ平面構造解析

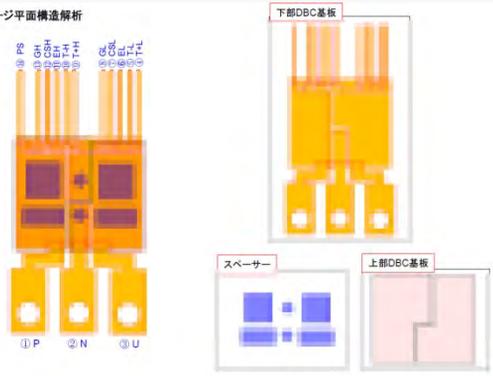
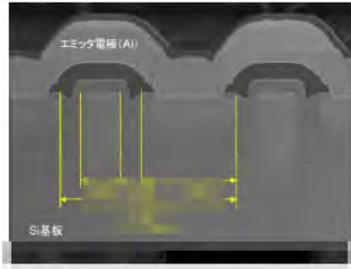


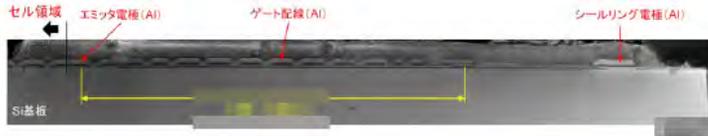
Fig. 2-2-5 パッケージレイアウト模式図

断面構造解析

セル部

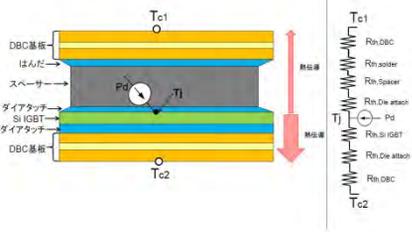


外周部



4-2. IGBT熱解析: 1-D Rth、Jc推定

4-1. IGBT熱解析: 熱抵抗モデル



位置	熱抵抗 (Rth)	材料	厚さ (mm)	熱伝導率 (W/mK)	面積 (mm²)	熱抵抗 (K/W)
上銅箔層	0.0001	銅	0.01	400	100	0.0001
絶縁層	0.0001	絶縁体	0.01	0.2	100	0.0001
添加物	0.0001	添加物	0.01	0.2	100	0.0001
下銅箔層	0.0001	銅	0.01	400	100	0.0001
はんだ	0.0001	はんだ	0.01	100	100	0.0001
スペース	0.0001	スペース	0.01	100	100	0.0001
ダイアタッチ	0.0001	ダイアタッチ	0.01	100	100	0.0001
Si IGBT	0.0001	Si IGBT	0.01	150	100	0.0001
ダイアタッチ	0.0001	ダイアタッチ	0.01	100	100	0.0001
DBC基板	0.0001	DBC基板	0.01	100	100	0.0001

・IGBT (スイッチあたり1つのトランジスタ)
 $R_{th,jc} = \dots \text{ } ^\circ\text{C/W per switch}$

・熱抵抗の成分は左表 (①~⑬)。
 ・IGBTチップの上側 (①~⑦) で支配的となっているのは、
 ・IGBTチップの下側のみの熱抵抗が

